

1.Description

Features of this design are a 150°C junction operating temperature, fast switching speed and improved repetitive avalanche rating.

2.2Features

- Advanced Process Technology
- Ultra Low On-Resistance
- 50°C Operating Temperature
- Fast Switching

2.1Features

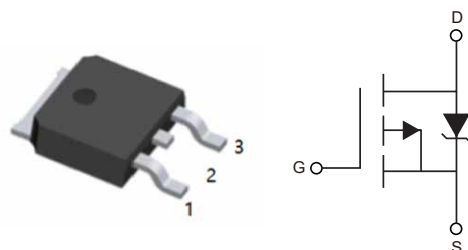
- $V_{DS(V)} = -55V$
- $I_D = -70A$
- $R_{DS(ON)} < 20m\Omega (V_{GS} = -10V)$

- Repetitive Avalanche Allowed up to T_{jmax}
- Some Parameters Are Different from IRF4905S

3.Pinning information

Pin	Symbol	Description
1	G	GATE
2	D	DRAIN
3	S	SOURCE

TO-252(DPAK)
top view



4.Absolute Maximum Ratings

Parameter		Symbol	Rating	Units
Continuous Drain Current, $V_{GS} @ 10V$ (Silicon Limited)	$T_c = 25^\circ C$	I_D	-70	A
Continuous Drain Current, $V_{GS} @ 10V$ (Silicon Limited)	$T_c = 100^\circ C$		-44	A
Continuous Drain Current, $V_{GS} @ 10V$ (Wire Bond Limited)	$T_c = 25^\circ C$		-42	A
Pulsed Drain Current ¹		I_{DM}	-280	A
Power Dissipation	$T_c = 25^\circ C$	P_D	170	W
Linear Derating Factor			1.3	W/°C
Gate-to-Source Voltage		V_{GS}	±20	V
Single Pulse Avalanche Energy ²		E_{AS} (Thermally limited)	140	mJ
Single Pulse Avalanche Energy Tested Value ⁶		E_{AS} (Tested)	790	mJ



Avalanche Current ¹	I_{AR}	See Fig.16a,	A
Repetitive Avalanche Energy ⁵	E_{AR}	16b, 15, 13	mJ
Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C
Soldering Temperature, for 10 seconds (1.6mm from case)		300	°C
Mounting Torque, 6-32 or M3 screw ⁷		10 lbf•in (1.1N•m)	

5.Thermal resistance rating

Parameter	Symbol	Typ	Max	Units
Junction-to-Case ⁸	R_{thJC}		0.75	°C/W
Junction-to-Ambient (PCB Mount, steady state) ^{7,8}	R_{thJA}		40	°C/W



6. Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Drain-to-Source Breakdown Voltage	$V_{(BR)DSS}$	$I_D = -250\mu\text{A}$, $V_{GS} = 0\text{V}$	-55			V
Breakdown Voltage Temp. Coefficient	$\Delta V_{(BR)DSS} / \Delta T_J$	Reference to 25°C , $I_D = -1\text{mA}$		-0.054		V/ $^\circ\text{C}$
Static Drain-to-Source On-Resistance	$R_{DS(ON)}$	$V_{GS} = -10\text{V}$, $I_D = -42\text{A}$ ³			20	m Ω
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = -250\mu\text{A}$	-1.1	-1.8	-2.5	V
Forward Transconductance	g_{FS}	$V_{DS} = -25\text{V}$, $I_D = -42\text{A}$		19		S
Drain-to-Source Leakage Current	I_{DSS}	$V_{DS} = -55\text{V}$, $V_{GS} = 0\text{V}$			-25	μA
		$V_{DS} = -44\text{V}$, $V_{GS} = 0\text{V}$, $T_J = 125^\circ\text{C}$			-200	μA
Gate-to-Source Forward Leakage	I_{GSS}	$V_{GS} = -20\text{V}$			100	nA
Gate-to-Source Reverse Leakage		$V_{GS} = 20\text{V}$			-100	nA
Total Gate Charge	Q_g	$I_D = -42\text{A}$, $V_{DS} = -44\text{V}$, $V_{GS} = -10\text{V}$ ³		120	180	nC
Gate-to-Source Charge	Q_{gs}			32		nC
Gate-to-Drain ("Miller") Charge	Q_{gd}			53		nC
Turn-On Delay Time	$t_{D(on)}$	$V_{DD} = -28\text{V}$, $I_D = -42\text{A}$ $R_G = 2.6\Omega$, $V_{GS} = -10\text{V}$ ³		20		ns
Rise Time	t_r			99		ns
Turn-Off Delay Time	$t_{D(off)}$			51		ns
Fall Time	t_f			64		ns
Internal Source Inductance	L_S	Between lead, and center of die contact		7.5		nH
Input Capacitance	C_{iss}	$V_{GS} = 0\text{V}$, $V_{DS} = -25\text{V}$ $f = 1\text{MHz}$		3500		pF
Output Capacitance	C_{oss}			1250		pF
Reverse Transfer Capacitance	C_{rss}			450		pF
Output Capacitance	C_{oss}	$V_{GS} = 0\text{V}$, $V_{DS} = -1\text{V}$, $f = 1\text{MHz}$		4620		pF
Output Capacitance	C_{oss}	$V_{GS} = 0\text{V}$, $V_{DS} = -44\text{V}$, $f = 1\text{MHz}$		940		pF
Effective Output Capacitance	$C_{oss\text{eff.}}$	$V_{GS} = 0\text{V}$, $V_{DS} = 0\text{V}$ to -44V ⁴		1530		pF



Diode Characteristics						
Continuous Source Current (Body Diode)	I_S	MOSFET symbol showing the integral reverse p-n junction diode.			-42	A
Pulsed Source Current (Body Diode) ¹	I_{SM}				-280	A
Diode Forward Voltage	V_{SD}	$T_J=25^{\circ}\text{C}, I_S=-42\text{A}, V_{GS}=0\text{V}$ ³			-1.3	V
Reverse Recovery Time	t_{rr}	$T_J=25^{\circ}\text{C}, I_F=-42\text{A}, V_{DD}=-28\text{V}$		61	92	ns
Reverse Recovery Charge	Q_{rr}	$di/dt=100\text{A}/\mu\text{s}$ ³		150	220	nC
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S+L_D)				

Notes:

1. Repetitive rating; pulse width limited by max. junction temperature.
2. Limited by T_{Jmax} , starting $T_J=25^{\circ}\text{C}$, $L=0.16\text{mH}$, $R_G=25\Omega$, $I_{AS}=-42\text{A}$, $V_{GS}=-10\text{V}$. Part not recommended for use above this value.
3. Pulse width $\leq 1\text{ms}$; duty cycle $\leq 2\%$.
4. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
5. Limited by T_{Jmax} , see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
6. This value determined from sample failure population. 100% tested to this value in production.
7. This is applied to D²Pak, when mounted on 1" square PCB (FR-4 or G-10 Material).
8. R_{θ} is measured at T_J approximately 90°C .



7.1 Typical Characteristics

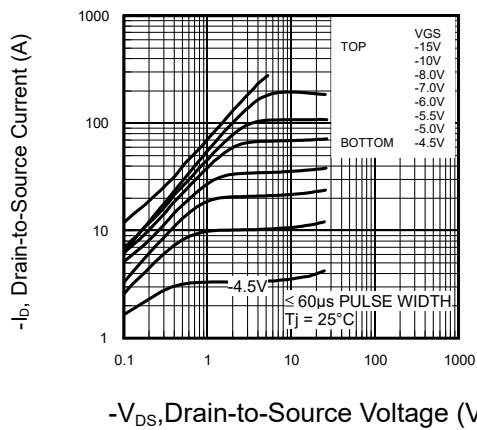


Figure 1: Typical On-Resistance vs. Gate Voltage

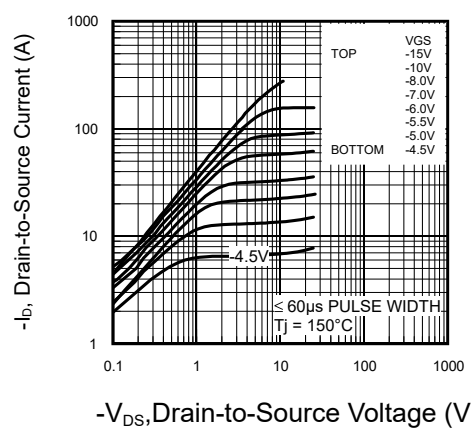


Figure 2: Typical Output Characteristics

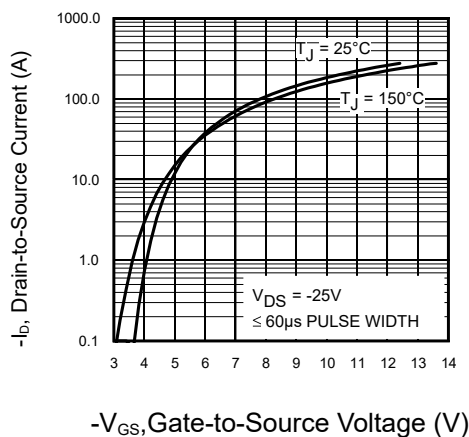


Figure 3: Typical Output Characteristics

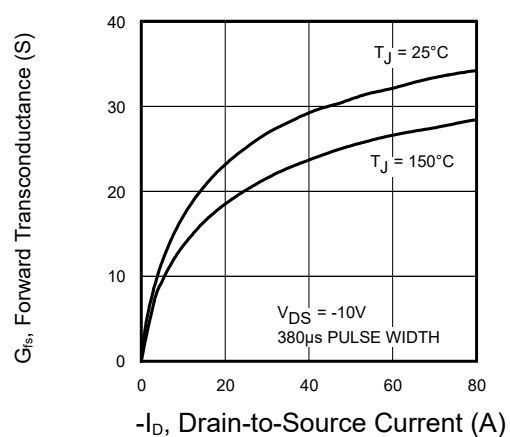


Figure 4: Typical Forward Transconductance Vs. Drain Current

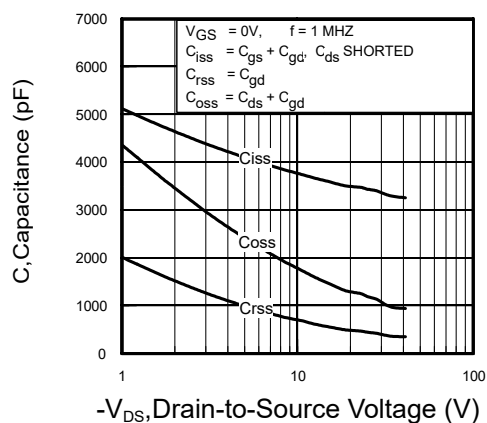


Figure 5: Typical Capacitance vs. Drain-to-Source Voltage

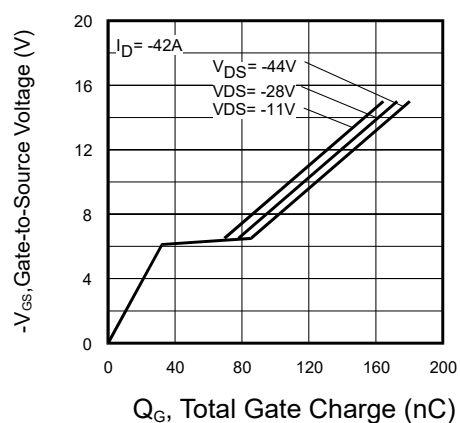


Figure 6: Typical Gate Charge Vs. Gate-to-Source Voltage



7.2 Typical Characteristics

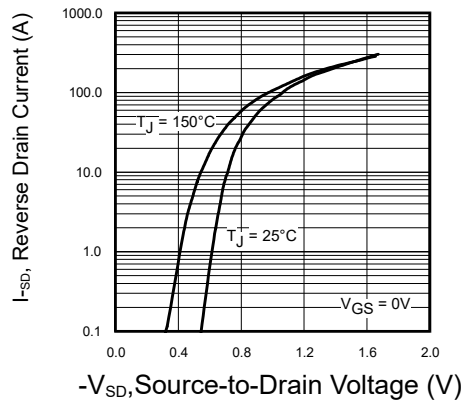


Figure 7: Typical Capacitance vs. Drain-to-Source Voltage

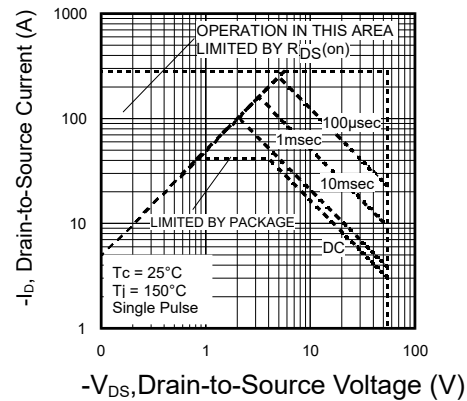


Figure 8: Maximum Safe Operating Area

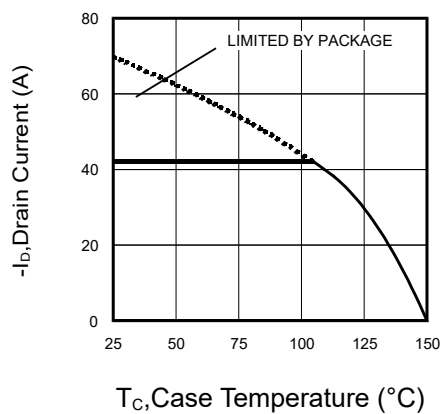


Figure 9: Maximum Drain Current Vs. Case Temperature

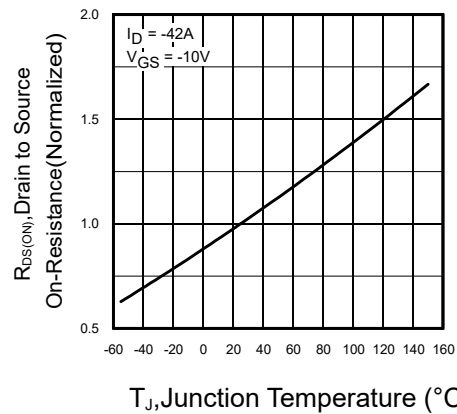


Figure 10: Normalized On-Resistance Vs. Temperature

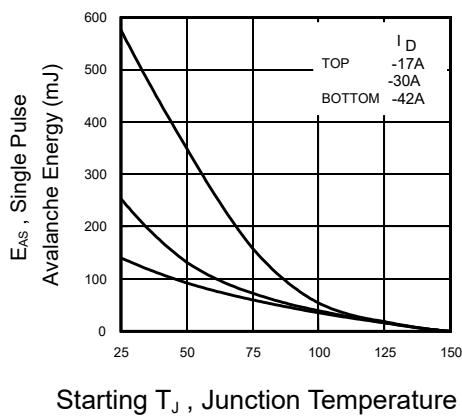


Figure 11: Typical On-Resistance vs. Drain Current

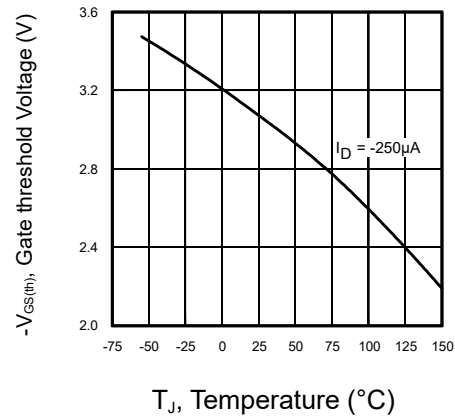
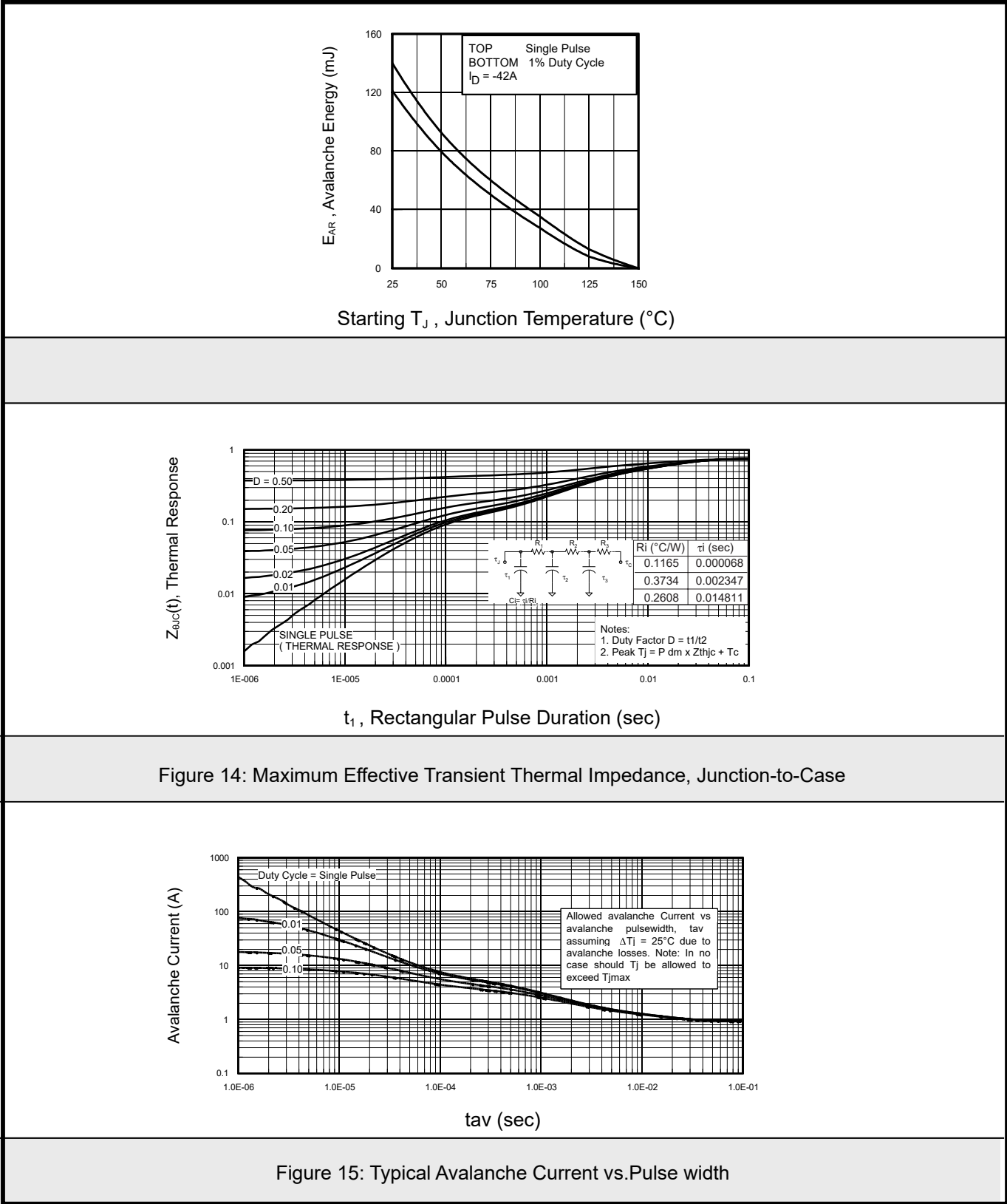


Figure 12: Threshold Voltage Vs. Temperature



7.3Typical Characteristics



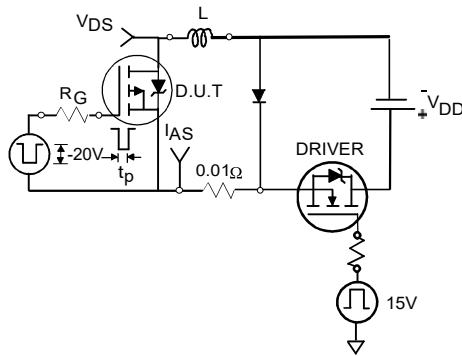


Figure 16a: Unclamped Inductive Test Circuit

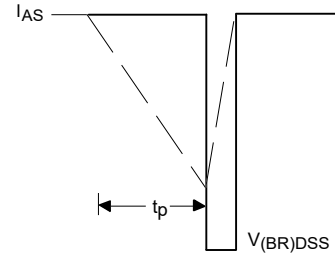


Figure 16b: Unclamped Inductive Waveforms

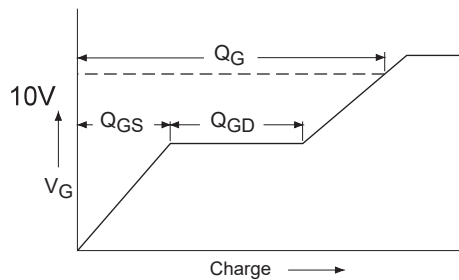


Figure 17a: Gate Charge Test Circuit

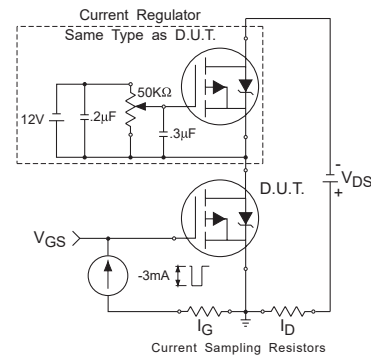


Figure 17b: Threshold Voltage Vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 13, 15:

1. Avalanche failures assumption: Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax} . This is validated for every part type.

2. Safe operation in Avalanche is allowed as long as T_{jmax} is not exceeded.

3. Equation below based on circuit and waveforms shown in Figures 16a, 16b.

4. $P_{D(ave)}$ = Average power dissipation per single avalanche pulse.

5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).

6. I_{av} = Allowable avalanche current.

7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 13).

t_{av} = Average time in avalanche.

D = Duty cycle in avalanche = $t_{av} \cdot f$

$Z_{thJC}(D, t_{av})$ = Transient thermal resistance.

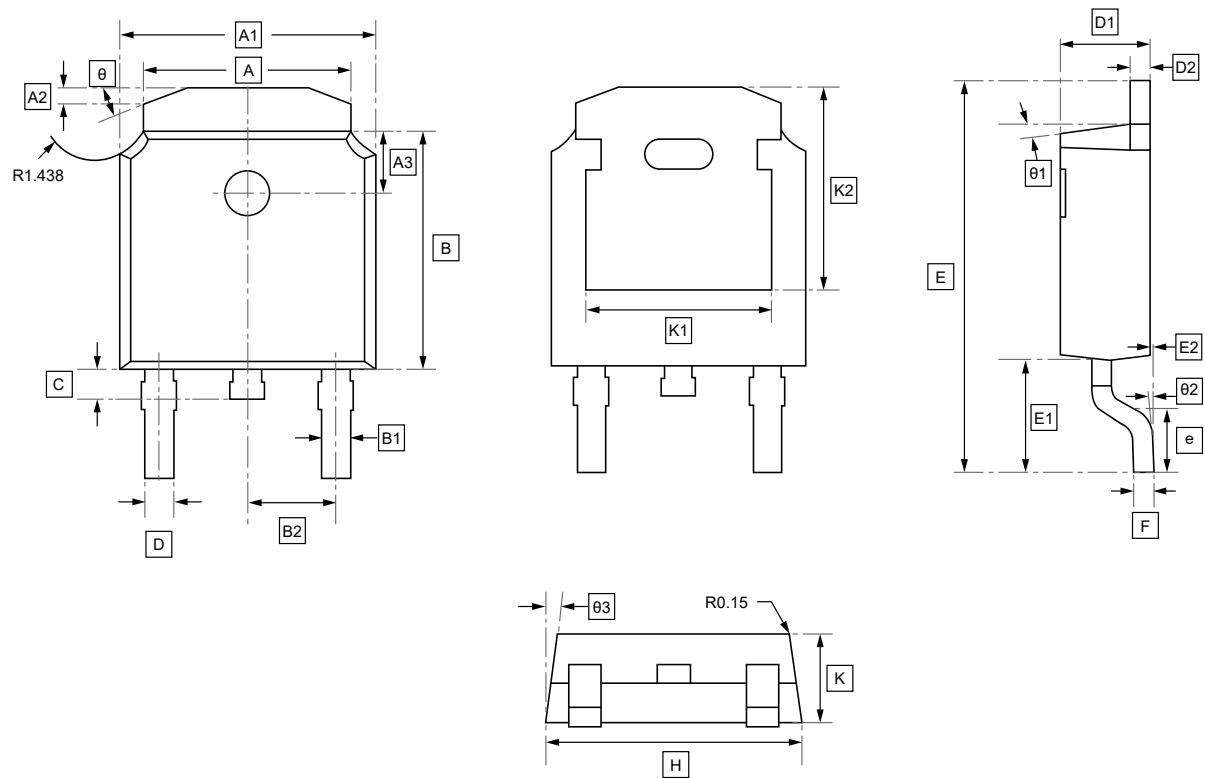
$P_{D(ave)} = 1/2 (1.3 \cdot BV \cdot I_{av}) = \Delta T / Z_{thJC}$

$I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$

$E_{AS(AR)} = P_{D(ave)} \cdot t_{av}$



8.TO-252 Package Outline Dimensions



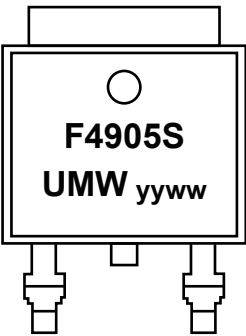
DIMENSIONS (mm are the original dimensions)

Symbol	A	A1	A2	A3	B	B1	B2	C	D	D1	D2	E
Min	5.20	6.50	0.40	1.40	6.00	0.740	2.286	0.60	0.74	2.15	0.50	9.80
Max	5.46	6.70	(typ)	1.80	6.20	0.940	(typ)	1.0	0.86	2.45	(typ)	10.40

Symbol	E1	E2	e	F	H	K	K1	K2	θ	θ1	θ2	θ3
Min	2.60	0.00	1.65	0.50	6.50	2.15	4.63	5.10	20°	7°	0°	7°
Max	3.20	0.127	(typ)	0.60	6.70	2.45	5.03	5.50	(typ)	(typ)	8°	(typ)



9.Ordering information



yy: Year Code
ww: Week Code

Order Code	Package	Base QTY	Delivery Mode
UMW IRF4905STRL	TO-252	2500	Tape and reel



10.Disclaimer

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